

New Editors – 2022

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Jie Han received BSc degree in electronic engineering from Tsinghua University, Beijing, China, in 1999 and the PhD degree from the Delft University of Technology, The Netherlands, in 2004. He is currently a Professor in the Department of Electrical and Computer Engineering at the University of Alberta. He was a NASA INAC (Institute for Nanoelectronics and Computing) Postdoctoral Fellow in the Department of Electrical and Computer Engineering at the University of Florida from 2004 to 2007. From 2007 to 2009, he worked as a Research Scientist at the Advanced Medical Diagnostics S.A./B.V. in Belgium. His research interests include approximate computing, stochastic computing, brain-inspired learning systems and neural networks, reliability, fault tolerance, nanoelectronic circuits and systems, and novel computational models for nanoscale and biological applications.

Dr. Han received the Best Paper Award at the IEEE/ACM International Symposium on Nanoscale Architectures (NANOARCH 2015) and Best Paper Nominations at NANOARCH 2016, the 25th IEEE/ACM Great Lakes Symposium on VLSI (GLSVLSI 2015), and the 19th International Symposium on Quality Electronic Design (ISQED 2018). He was nominated for the 2006 Christiaan Huygens Prize of Science by the Royal Dutch Academy of Science (Koninklijke Nederlandse Akademie van Wetenschappen – KNAW, Christiaan Huygens Wetenschapsprijs). His work was recognized by the 125th anniversary issue of *Science*, for developing a theory of fault-tolerant nanocircuits (2003).

Dr. Han is an Associate Editor for the IEEE Transactions on Emerging Topics in Computing (TETC), IEEE Transactions on Nanotechnology, IEEE Circuits and Systems Magazine (CASM), and IEEE Open Journal of the Computer Society and Microelectronics Reliability (Elsevier Journal). He was General Chair for the IEEE/ACM International Symposium on Nanoscale Architectures (NANOARCH 2021), GLSVLSI 2017 and the IEEE International Symposium on Defect and Fault Tolerance in VLSI and Nanotechnology Systems (DFT 2013), and Technical Program Committee (TPC) Chair for GLSVLSI 2016 and DFT 2012. He served as a TPC Member for several international conferences and symposia, including the Design Automation conference (DAC 2017–2019), Design, Automation & Test in Europe Conference (DATE 2014–2019, 2021/2), International Conference in Computer-aided Design (ICCAD 2018–2019), and DFT 2011–2021. He is a senior member of the Institute of Electrical and Electronics Engineers (IEEE), a member of the Association for Computing Machinery (ACM), and a member of the American Society for Engineering Education (ASEE).



Aibin Yan received his PhD and MSE degrees from Hefei University of Technology and the University of Science and Technology of China, respectively. Currently, he is an IEEE/CCF Senior Member and a member of the editorial board of the *Microelectronics & Computer* journal. He is a PhD supervisor and an associate professor at the school of computer science and technology, Anhui University (AHU),

China. During 2018–2019, he visited Kyushu Institute of Technology, Japan, under the support of China Scholarship Council, and worked under the supervision of Prof. Xiaoqing WEN, an IEEE Fellow, for a full year. During that year, he participated in chip design, tape out and test. In 2021, he created the AHU Institute of Chip Design and Test, and now serves as its director. He has served as a Session Chair at IEEE ISCAS (2020), IEEE ITC-Asia (2021) and CCF-DAC (2021), Publicity Chair for IEEE ATS (2018) and 3D-Chip Forum of China Fault Tolerance Conference (2021), Forum Chair of China National Computer Congress (2021), and General Chair of the 1st CCF Inspiring Conference and National Advanced IC Design and Test Summit Forum. He also served as Doctoral Dissertation Reviewer of the Degree Center of the Ministry of Education, on Committee on Fault Tolerant Computing of CCF, on Committee on Integrated

Circuit Design of CCF, and as Reviewer for IEEE TCAD, IEEE TIE, IEEE TAES, IEEE TETC, IEEE TCASI/II, IEEE TVLSI, IEEE Tnano, IEEE TDMR, etc. He has presented his research numerous times at International Conferences, such as IEEE DAC, DATE, ICCD, DSN, ISCAS, ATS, VTS, DSA, ITC-Asia, etc. He received a Best Paper Award in China Test Conference (2018) and received an Award in China "Challenge Cup" Extracurricular Academic and Technological Works Competition (Tutor). Four of his papers published in IEEE TCAD/TETC/TVLSI were selected as ESI Highly Cited Papers. Five of his master's students received 20,000 RMB China Scholarship Award in 2020/2021.

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